Search Notes Application/Control No. Applicant(s)/Patent Under Reexamination TISCHER, STEVEN Examiner Haile, Awet A Art Unit 2616

SEARCHED					
Class	Subclass	Date	Examiner		
370	465	4/8/2008	Awet Haile		
370	401	4/8/2008	Awet Haile		
370	238	4/8/2008	Awet Haile		
370	476	4/8/2008	Awet Haile		
370	395	4/8/2008	Awet Haile		

SEARCH NOTES					
Search Notes	Date	Examiner			
East search	4/8/2008	Awet Haile			

INTERFERENCE SEARCH					
Class	Subclass	Date	Examiner		

U.S. Patent and Trademark Office Part of Paper No.: